

## FRAUNHOFER INSTITUTE FOR INTEGRATED SYSTEMS AND DEVICE TECHNOLOGY IISB



1 Thermal characterization of power modules mounted on a water-glycol cooled heat sink

# Fraunhofer IISB

Schottkystrasse 10 91058 Erlangen Germany

# **Contact:**

Dr. Juergen Leib Phone: +49 9131 761 615 juergen.leib@iisb.fraunhofer.de

## www.iisb.fraunhofer.de



# **THERMAL CHARACTERIZATION** RESISTANCE R<sub>TH</sub> AND IMPEDANCE Z<sub>TH</sub> MEASUREMENTS

#### Fields of research and service

- Thermal characterization of new packaging concepts, materials, devices and technologies for power electronic devices
- Power module characterization acc. to AQG 324
- Static and dynamic thermal measurements (R<sub>th</sub>, Z<sub>th</sub>)
- Heat sinks for single and multi devices (up to 20 samples per heat sink)
- Design and assembly of power modules for testing (silver sintering, soldering, wire bonding)
- FEM-simulation of thermal behavior from semiconductor to coolant
- Workshops for test result interpretation

#### **Measurement system**

- Temperature acquisition via device under test (indirect measurement principle)
- Direct temperature measurement by thermography, PT100 and thermo-couples
- Heating current from 0.1 A up to 2000 A
- Heating voltage up to 35 V
- Heating and cooling power up to 20 kW
- Coolant temperatures from 60 up to + 350 °C possible
- Coolant flow up to 25 l/min
- Maximum pressure: 8 bar



#### **Devices for testing**

- IGBTs, MOSFETs, JFETs, thyristors
- Resistors
- Schottky-diodes, pn-diodes
- Si, SiC and GaN devices

### **Packaging for testing**

- Power modules with or without baseplate
- PCB-boards with discretes (To-devices, D<sup>2</sup>Paks, etc.)
- Direct or indirect water cooled systems
- Liquid and air cooled devices
- With or without housing or molding
- In-house test layouts and samples
- Packaging services

#### **Additional services**

- Foster/Cauer network calculation and parameter extraction
- Thermal management consulting
- FEM simulations
- Statistical analysis









- 2 Power module during thermal impedance measurement
- 3 Device under test
- 4 Thermography
- 5 FEM mulation
- 6 Example of thermal impedance measurement